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**1 Invited paper from Awardees of the most influential paper from ICSE'15: ViewPoints:
meaningful relationships are difficult!**



Bashar Nuseibeh, Jeff Kramer, Anthony Finkelstein

May 2003 **Proceedings of the 25th international conference on Software engineering**

Full text available: [pdf\(686.74 KB\)](#)

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Additional Information: full citation, abstract, references

The development of complex systems invariably involves many stakeholders who have different perspectives on the problem they are addressing, the system being developed, and the process by which it is being developed. The ViewPoints framework was devised to provide an organisational framework in which these different perspectives, and their relationships, could be explicitly represented and analysed. The framework acknowledges the inevitability of multiple inconsistent views, promotes separation ...

2 2nd international workshop on living with inconsistency



Steve Easterbrook, Marsha Chechik

July 2001 **Proceedings of the 23rd international conference on Software engineering**

Full text available:

[pdf\(45.96 KB\)](#) [Publisher Site](#)

Additional Information: full citation, abstract, references, index terms

In software engineering, there has long been a recognition that inconsistency is a fact of life. Evolving descriptions of software artefacts are frequently inconsistent, and tolerating this inconsistency is important if flexible collaborative working is to be supported. This workshop will focus on reasoning in the presence of inconsistency, for a wide range of software engineering activities, such as building and exploring requirements models, validating specifications, verifying correctness ...

3 TRAM: a tool for requirements and architecture management



Jun Han

January 2001 **Australian Computer Science Communications , Proceedings of the 24th Australasian conference on Computer science**, Volume 23 Issue 1

Full text available:

[pdf\(1.17 MB\)](#) [Publisher Site](#)

Additional Information: full citation, abstract, references

Management of system requirements and system architectures is part of any software engineering project. But it is usually very tedious and error prone. In particular, managing the traceability between system requirements and system architectures is critical but difficult. In this paper, we introduce a tool, TRAM, for managing system requirements, system architectures and more importantly the traceability between them. Its primary design objective is "being practical" and ready for practitioners ...

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Keywords: requirements management, software engineering tools, system architectures



4 Workshop and conference summaries: 2nd international workshop on living with inconsistency (IWLWI01)

Steve Easterbrook, Marsha Chechik

November 2001 **ACM SIGSOFT Software Engineering Notes**, Volume 26 Issue 6

Full text available: [PDF \(377.96 KB\)](#) Additional Information: [full citation, abstract, references](#)

IWLWI-01 --- The Second International Workshop on Living with Inconsistency, took place in Toronto, Canada, on May 13, 2001 as part of ICSE-01. The following is a short overview of this workshop.

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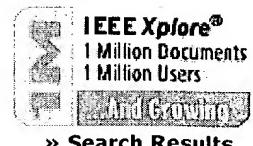
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